

# $4\pi$ Silicon Hybrid Detector with Charged Particle Identification and Highest Position Resolution for an Experiment at EIC

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Brookhaven National Laboratory

SILICON PIXEL-BASED PARTICLE VERTEX AND TRACKING  
DETECTORS TOWARDS THE US ELECTRON ION COLLIDER  
WORKSHOP, September 02-04, 2020



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NATIONAL LABORATORY  
*a passion for discovery*



# Project Member: International Collaboration

## Project members have extensive record on the construction of silicon detectors:

- Silicon strip detector
- Silicon pixel detector
- Silicon hybrid pixel
- SOIMPXD
- UFSD: LGAD, AC-LAGD
- Silicon readout electronic
- Silicon assembly
- Cooling system
- Integration
- Commissioning
- And more

### Project Members:

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Argonne National Laboratory, 9700 S. Cass Avenue, Lemont, IL 60439, United States

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Simone Mazza, Hartmut Sadrozinski, Bruce Schumm, and Abraham Seiden  
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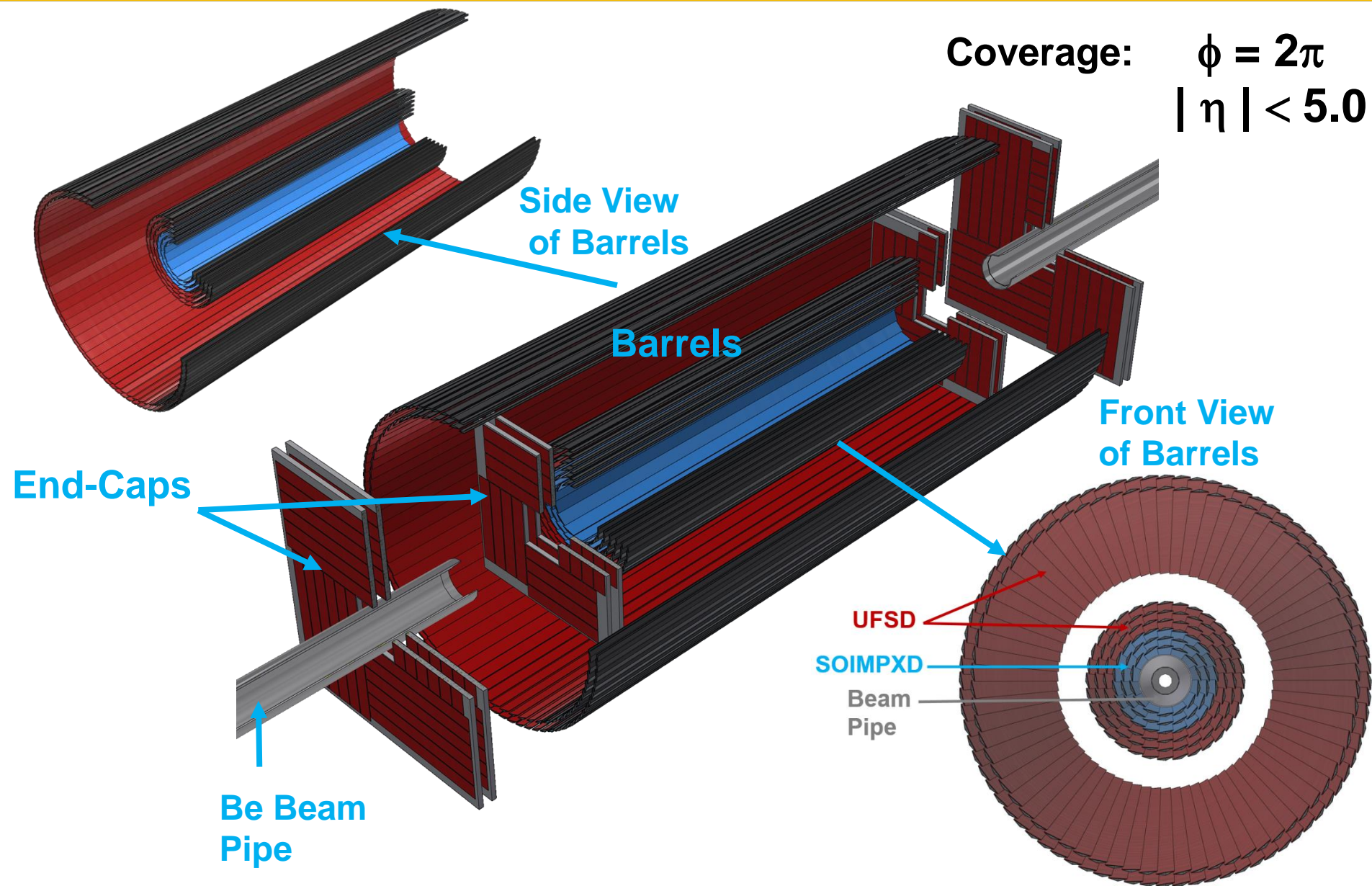
Kazuhiko Hara

University Tsukuba, Tsukuba, Japan



## We welcome people/institutions to join the project

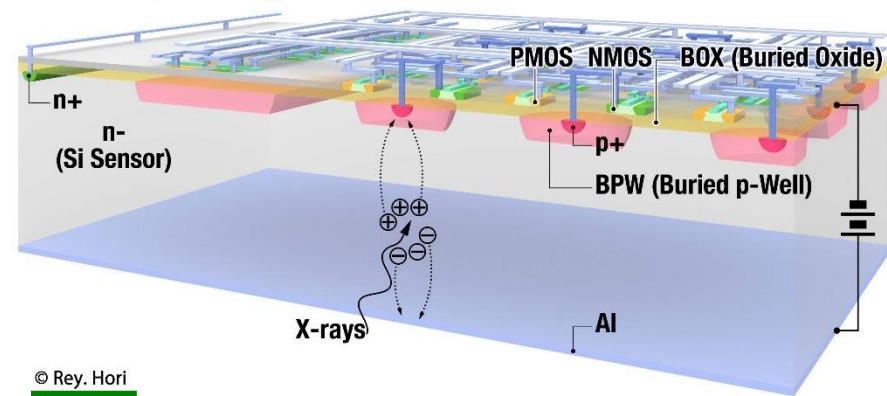
# $4\pi$ Silicon Hybrid Detector = SOIMPXD + UFSD





# Why Silicon-On-Insulator Monolithic PiXeI Detector (SOIMPXD) ?

- Monolithic device. No mechanical bonding.
- Fabricated with semiconductor process only → High reliability and Low Cost.
- High Resistive fully depleted sensor (50  $\mu\text{m}$ ~700  $\mu\text{m}$  thick) with Low sense node capacitance → Large S/N.
- On Pixel processing with CMOS circuits.
- No Latch up and very low Single Event cross section.
- Can be operated in wide temperature (1K-570K) range.
- Based on Industry Standard Technology



# Why Silicon-On-Insulator Monolithic PiXel Detector (SOIMPXD) ?

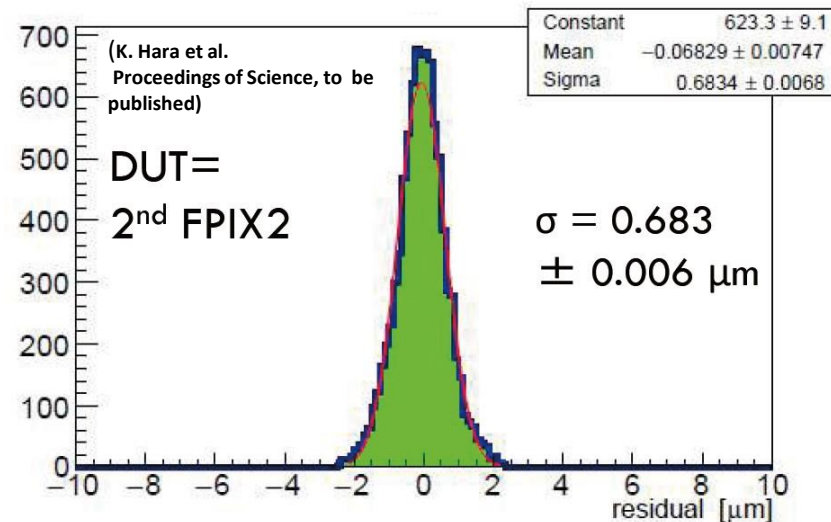
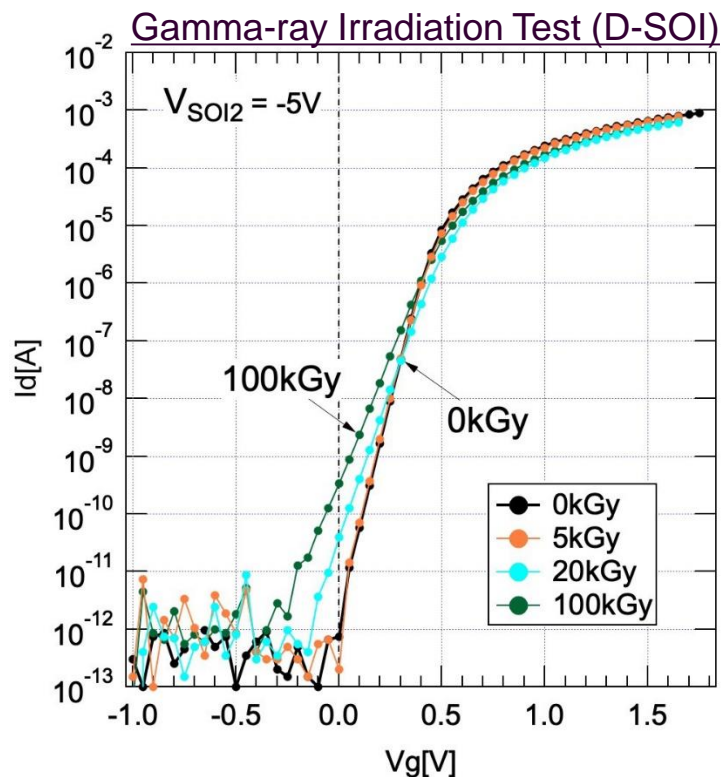
- **SOIMPXD** has the best tracking position resolution in the world **0.68  $\mu\text{m}$** , high radiation tolerance more than **10 Mrad (Si)**, time resolution  $\sim 1\mu\text{s}$ , and low material budget.

Courtesy of Prof. Yuso Arai

## Tracking Resolution:

**Proton beam 120 GeV @ FTBF 2018**

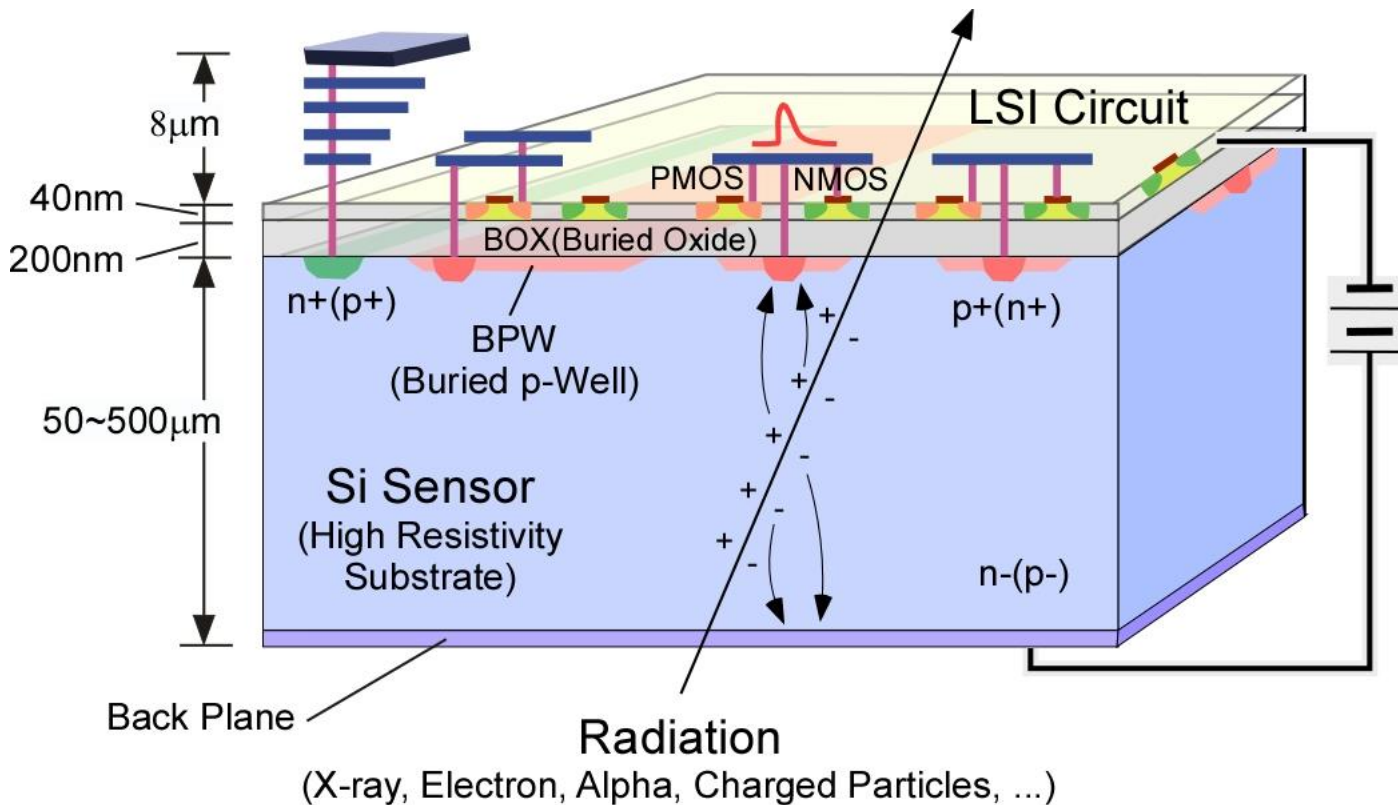
D. Sekigawa et al. TIPP2018



Detector	Pixel size	Resolution
ATLAS Pix	13.75 $\mu\text{m}$	1.1 $\mu\text{m}$
DEPFET	24 $\mu\text{m}$	1.4 $\mu\text{m}$
SOFIST	20 $\mu\text{m}$	<b>1.2 <math>\mu\text{m}</math></b>
FPIX	8 $\mu\text{m}$	<b>0.68 <math>\mu\text{m}</math></b>

# Silicon-ON-Insulator Monolithic PiXeI Detector (SOIMPXD)

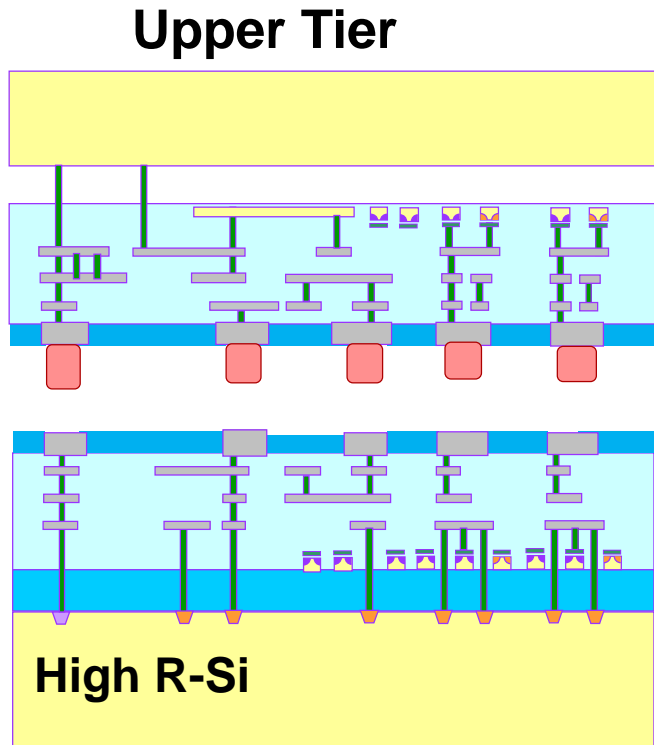
Courtesy of Prof. Yuso Arai



Monolithic Detector having fine resolution of silicon process and high functionality of CMOS LSI by using a SOI Pixel Technology.

# Silicon-On-Insulator Monolithic Pixel Detector (SOIMPXD)

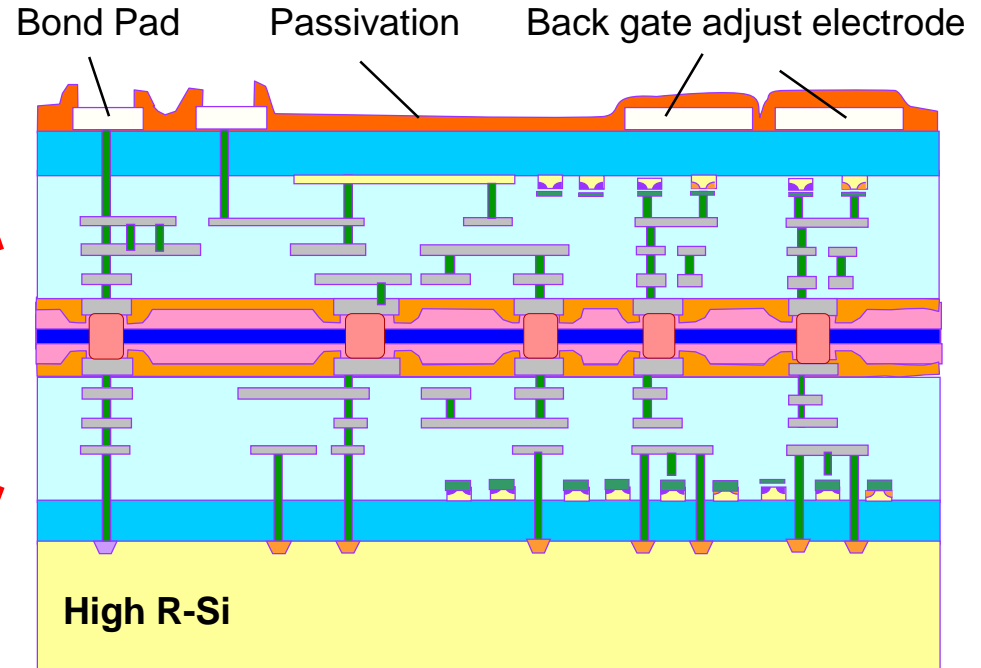
## 3D Vertical Integration



**Lower Tier**



## **SOFIST Ver. 4**

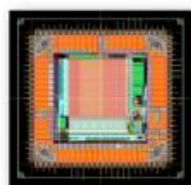


**Upper and Lower Tier chips are produced in a same wafer and bonded chip to chip.**

# Extensive Program Achieved on SOIMPXD using Beam Test at FNAL

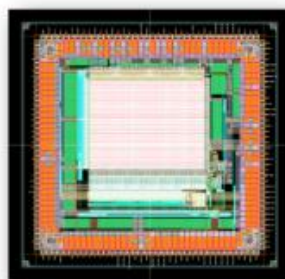
SOFIST1

Beam test at FNAL  
in Jan. 2017  
Analog signal



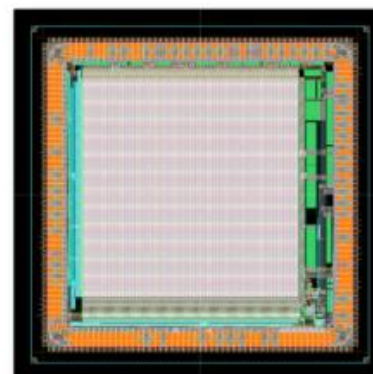
SOFIST2

Beam test at FNAL  
in Feb. 2018  
Analog signal or  
Timestamp



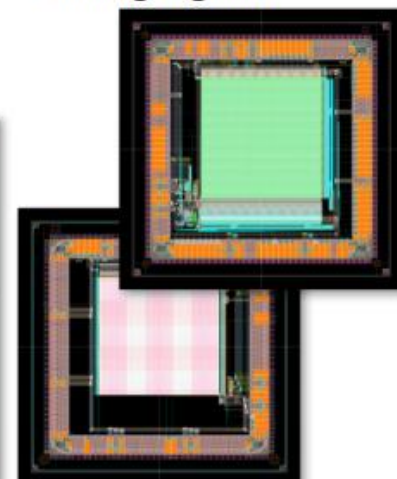
SOFIST3

Beam test at FNAL  
in Feb. 2019  
Analog signal and  
Timestamp



SOFIST4 (3D)

Beam test at FNAL  
in Feb. 2020  
Analog signal

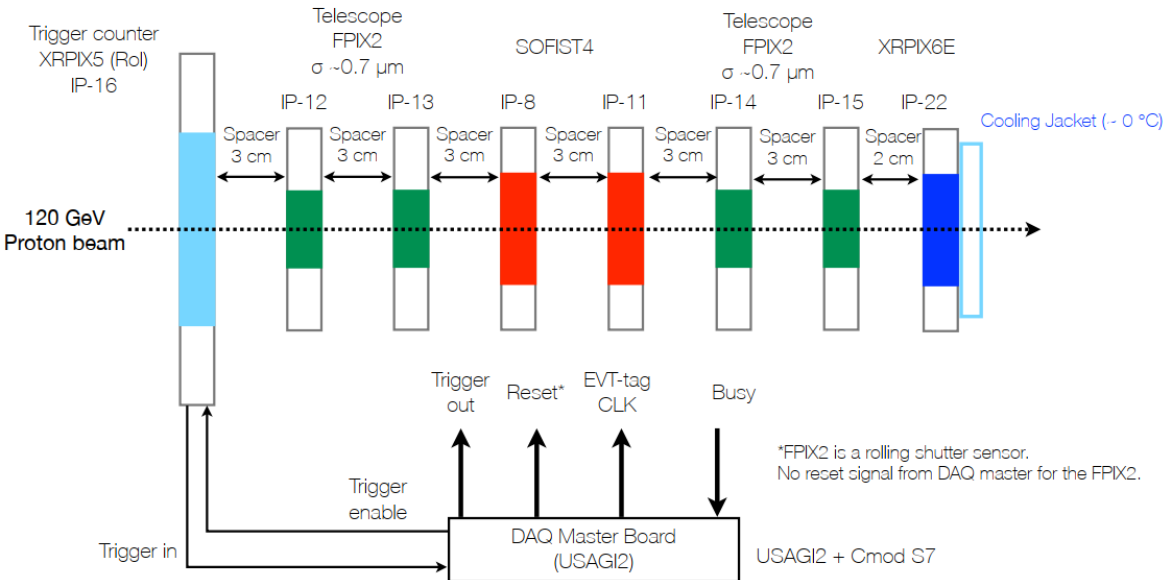


Courtesy of Miho Yamada

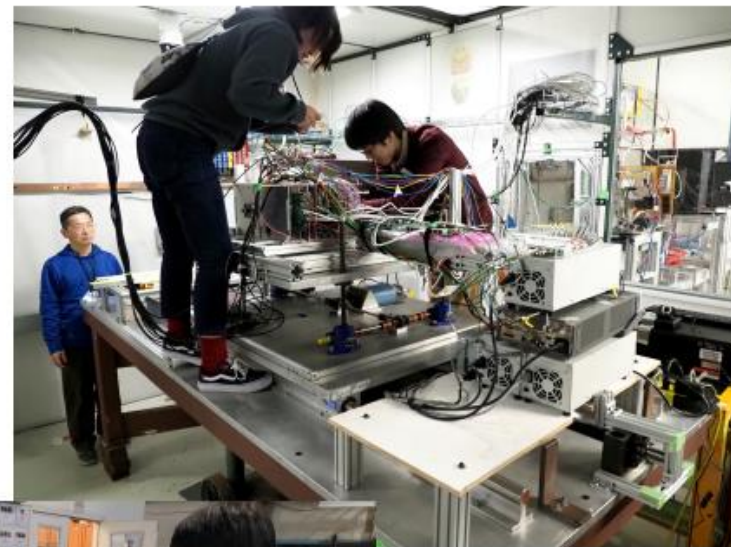
Chip Size (mm <sup>2</sup> )	2.9 × 2.9	4.45 × 4.45	6 × 6	4.45 × 4.45
Pixel Size (μm <sup>2</sup> )	20 × 20	25 × 25	30 × 30	20 × 20
Pixel Array	50 × 50 (Analog Signal)	64 × 64 (Time Stamp) 16 × 64 (Analog Signal)	128 × 128 (Analog signal and Time stamp)	104 × 104 (Analog signal and Time stamp)
Functions (Pixel)	Pre. Amplifier (CSA) Analog signal memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 2) Analog signal memory (2 hits) or Time stamp memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)
Functions (On Chip)	Column ADC (8 bit)	Column ADC (8 bit) Zero-suppression logic	Column ADC (8 bit)	Column ADC (8 bit)
Wafer	FZ <i>n</i> -type (Single SOI)	Cz <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)
Wafer Resistivity (kΩ-cm)	2 ≤	1 ≤	3 - 10	3 - 10
Status	Delivered (Dec. 2015) Position resolution ~1.4 μm	Delivered (Jan. 2017) Time resolution ~1.55 μs	Delivered (May. 2018) Under evaluation	Delivered (Jan. 2019 ~)



# SOIMPXD @ FBTF Feb. 26<sup>th</sup> - Mar 8<sup>th</sup>, 2020: 120 GeV Proton Beam

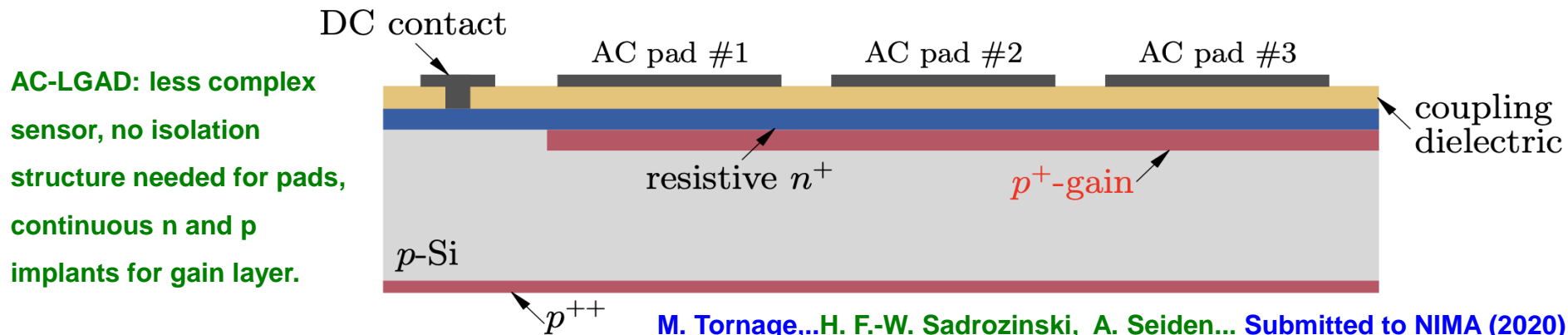


Courtesy of Miho Yamada



# Why Ultra Fast Silicon Detector (UFSD) ?

- **Ultra Fast Silicon Detector (UFSD)** are thin pixelated silicon sensors - based on the Low Gain Avalanche Detector (LGAD) design which uses one extra implant during the sensor fabrication to achieve an intense electric field in a few micron region near the detector junction. The large electric field is able to start an avalanche multiplication for the collected electrons. The resulting large and fast signal allows the measurement of the particle hit time determination to be improved **from nanoseconds to picoseconds**. Developed by CNM Barcelona (Spain) first, HPK Hamamatsu (Japan), FBK Trento (Italy), and BNL (US).
- Can deliver the timing accuracy needed for ToF/PID and physics at the EIC
- Can be arranged in an array covering large areas as conventional silicon detectors for tracking
- The AC-LGADs are actually fairly simple compared to for example strip detectors (no large number of individual strips with polysilicon resistors) and not exceptionally difficult to fabricate, BNL was able to make them. Should result in reduced cost.



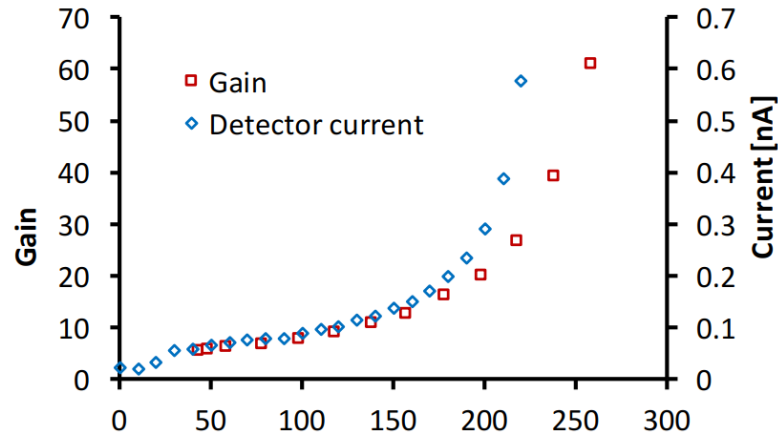
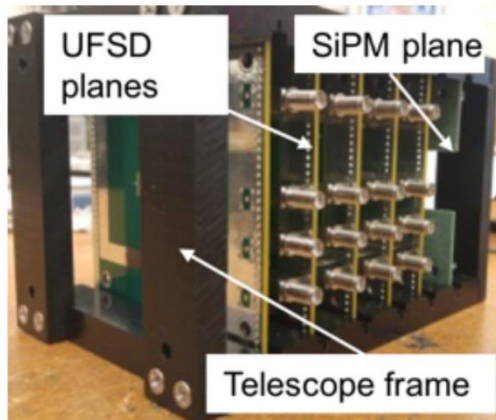
# UFSD: Beam Test at CERN

**Results:** Beam test with pions of 180 GeV/c momentum at CERN

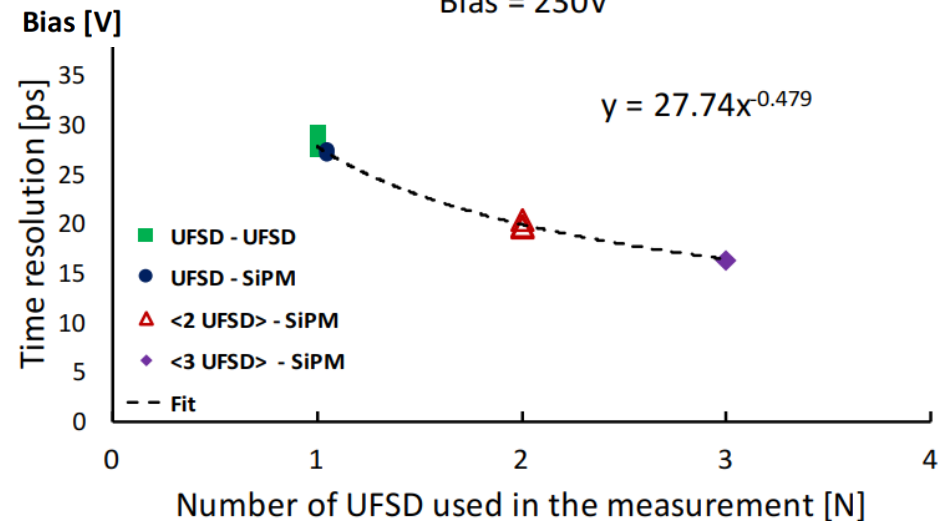
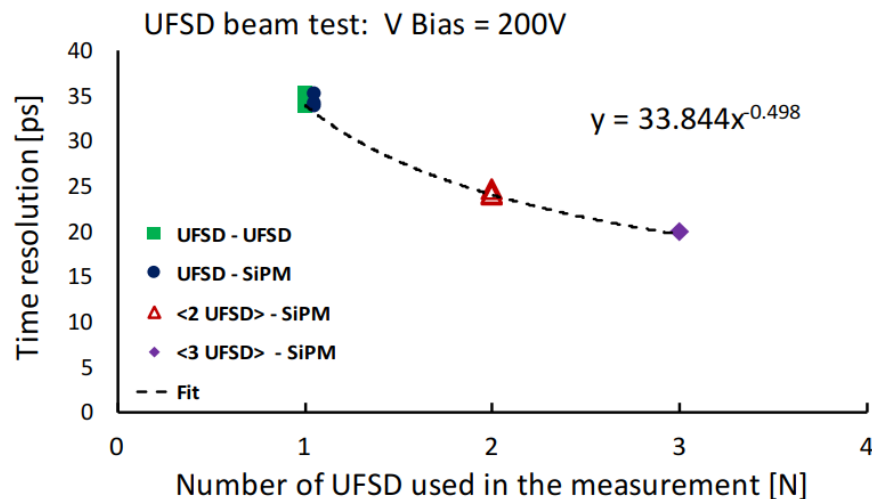
for the first production of 45  $\mu\text{m}$  thick Ultra-Fast Silicon Detectors (LGAD).

**16 ps time resolution with three layers UFSD achieved, best in the world.**

N. Cartigali,...,  
H. F.-W. Sadrozinski,  
A. Seiden...  
NIM 850 (2017) 83.



Bias = 230V

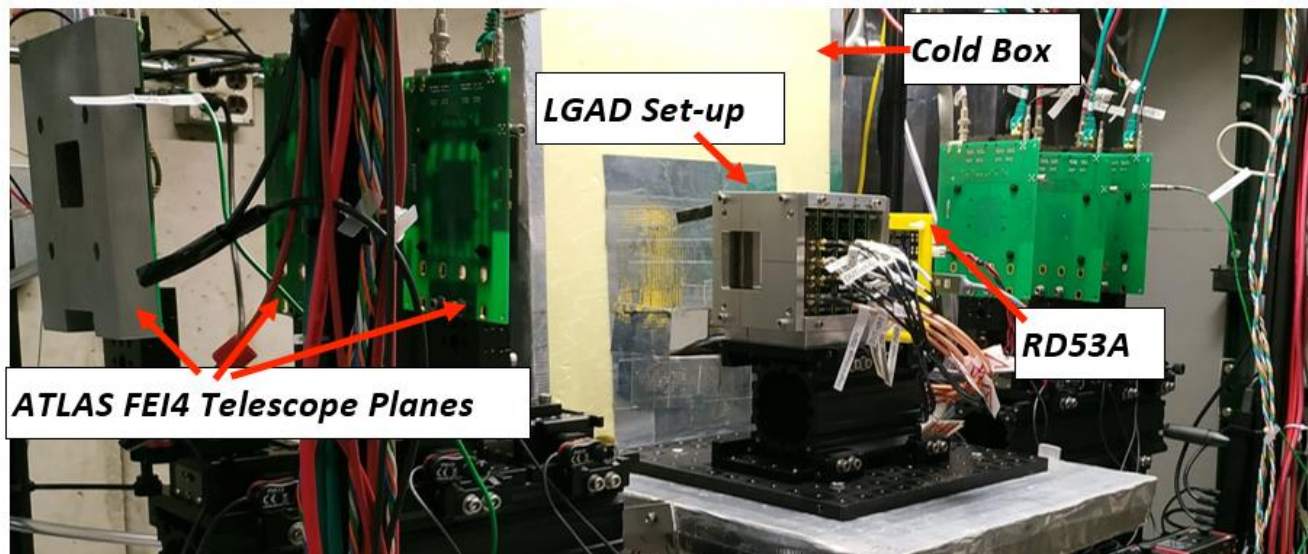
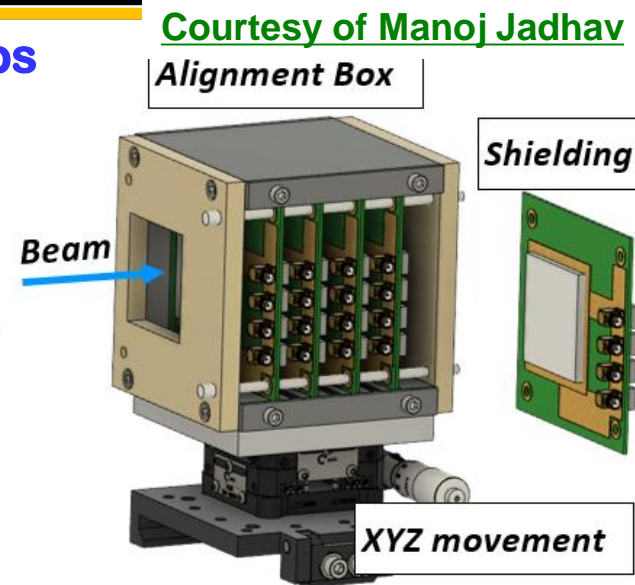




# UFSD: Beam Test at Fermi Lab 2019

Achieved by ANL (Argonne) and UC (Santa Cruz) groups

- ❖ Proton Beam with momentum 120 GeV
- ❖ Objective of evaluation of time resolution for minimum ionising particles and effect of more than one sensor plane
- ❖ Four LGAD sensors placed in alignment box mounted on XYZ stage
- ❖ Sensors HPK 1.2 ( $35\mu\text{m}$ ), 3.1( $50\mu\text{m}$ ) were tested
- ❖ Cold temperature measurements at  $-30\text{ }^{\circ}\text{C}$  is achieved using FP89-ME Julabo Chiller
- ❖ Data were collected in spills of 4 sec duration and instantaneous trigger rate between 1 and 5 Hz were achieved





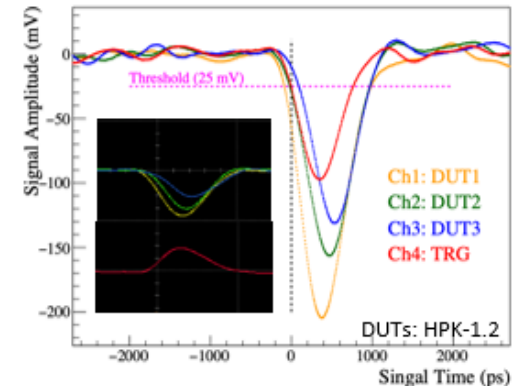
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Courtesy of Manoj Jadhav

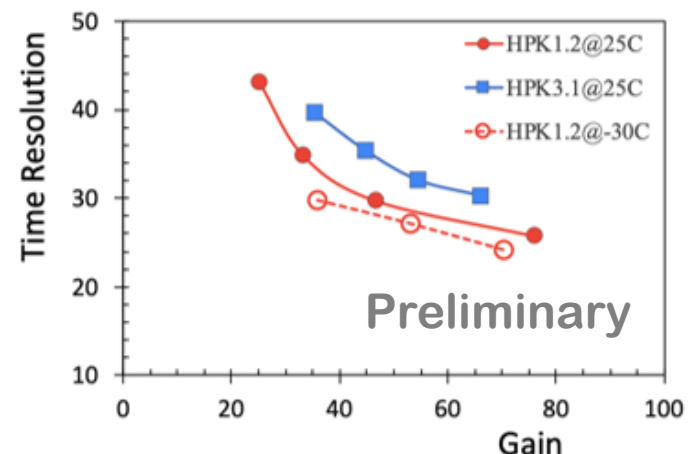
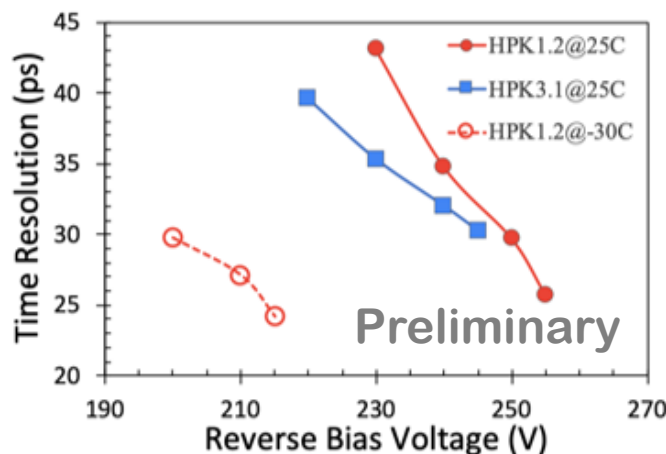
## Timing Resolution

- ❖ Sensor leakage current were stable  $\sim 10\text{-}20$  nA
- ❖ Very short rise time of  $\sim 350\text{-}400$  ps were obtained
- ❖ Time resolution improvement at low temperature
- ❖ Figure below shows timing resolution as a function of bias voltage and the gain



## Description of tested LGAD

Sensors HPK	Type	Thickness ( $\mu\text{m}$ )	Pad Area ( $\text{mm}^2$ )	Capacitance (pF)	Rise Time (10-90%) (ps)	Breakdown Voltage (V)
1.2	n-on-p	35	$1.3 \times 1.3$	5.35	375	270
3.1	n-on-p	50	$1.3 \times 1.3$	3.9	470	245



# UFSD: Beam Test at Fermi Lab 2019

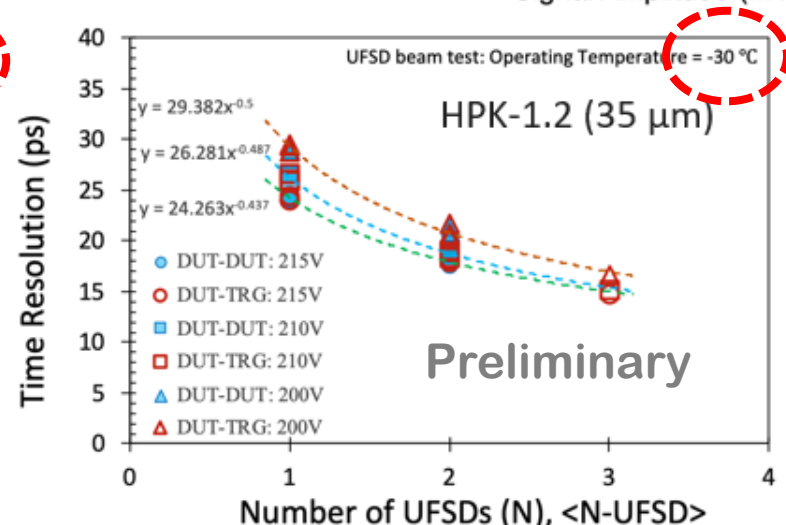
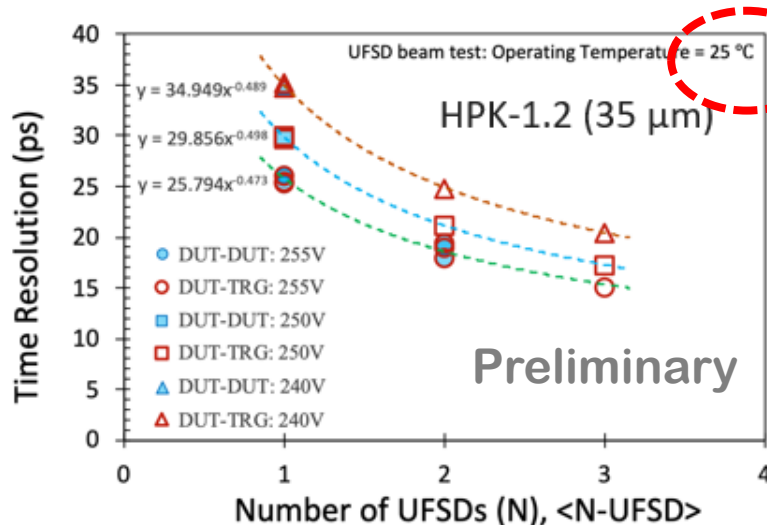
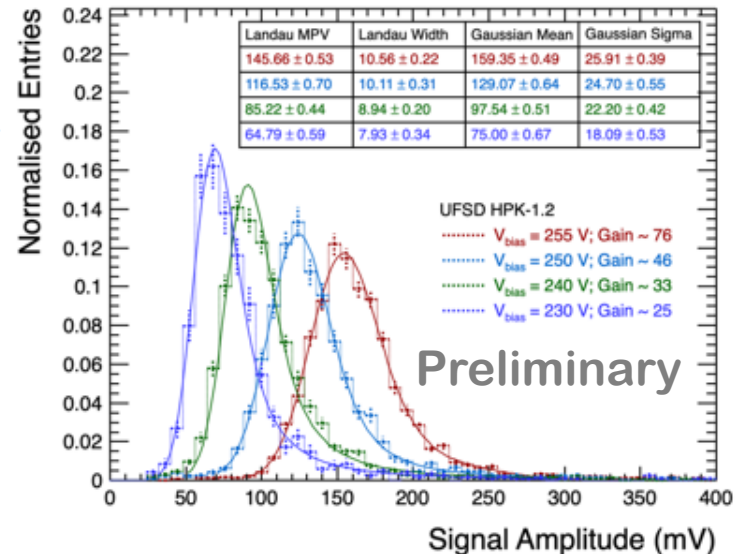
Achieved by ANL (Argonne) and UC (Santa Cruz) groups

Courtesy of Manoj Jadhav

Timing Resolution: to be submitted for publication soon

- ❖ Achieved timing resolution of about **14.73 ps**
- ❖ Normalized signal amplitude vs. Bias Voltage
- ❖ Time Resolution vs. No. Of UFSDs

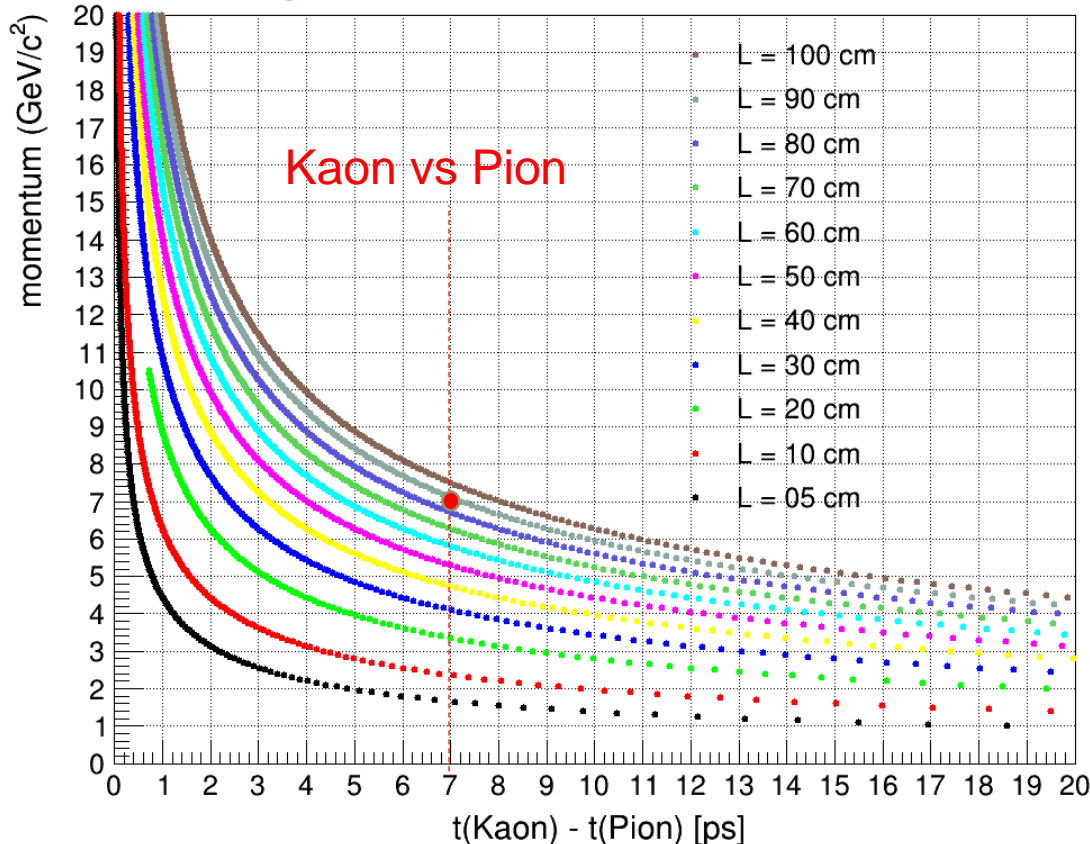
HPK1.2	$V_{\text{bias}} = 240\text{V}$ (25 °C)	$V_{\text{bias}} = 255\text{V}$ (25 °C)	$V_{\text{bias}} = 215\text{V}$ (-30 °C)
N = 1	34.78 ps	25.7 ps	24.17 ps
N = 2	24.77 ps	18.79 ps	18.11 ps
N = 3	-	15.04 ps	14.73 ps



# Why Ultra Fast Silicon Detector (UFSD) ?

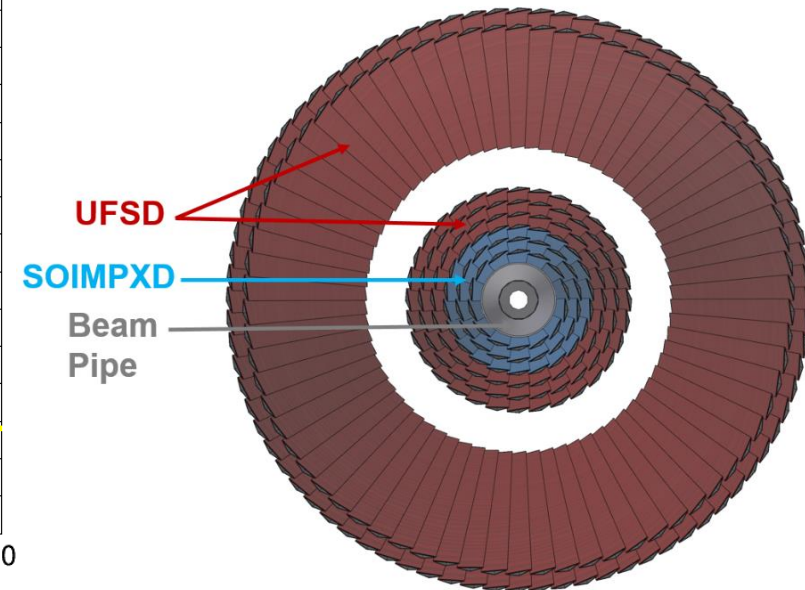
- 3 layers UFSD ( 35  $\mu\text{m}$ )  $\rightarrow$  15 ps time resolution (measured)
- Goal: UFSD (AC-LGAD) with 20  $\mu\text{m}$  thickness of sensor  $\rightarrow$  5 to 10 ps time resolution
- **Basic Math:** Two particles with the same momentum but different masses have different

**Time of Flight: this can be used for PID**



$$T_1 - T_2 = \frac{L}{c} \left( \sqrt{1 + \frac{m_1^2}{p^2}} - \sqrt{1 + \frac{m_2^2}{p^2}} \right)$$

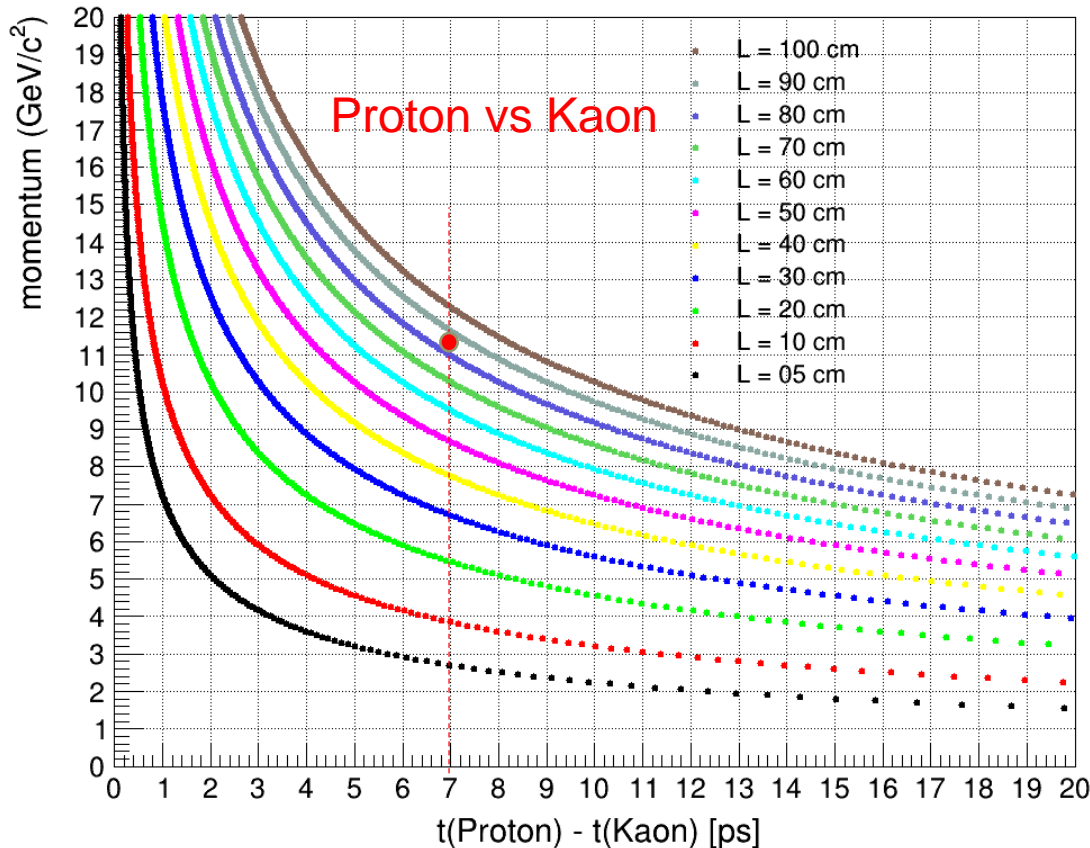
$L$ : path length (Silicon Barrel Position)



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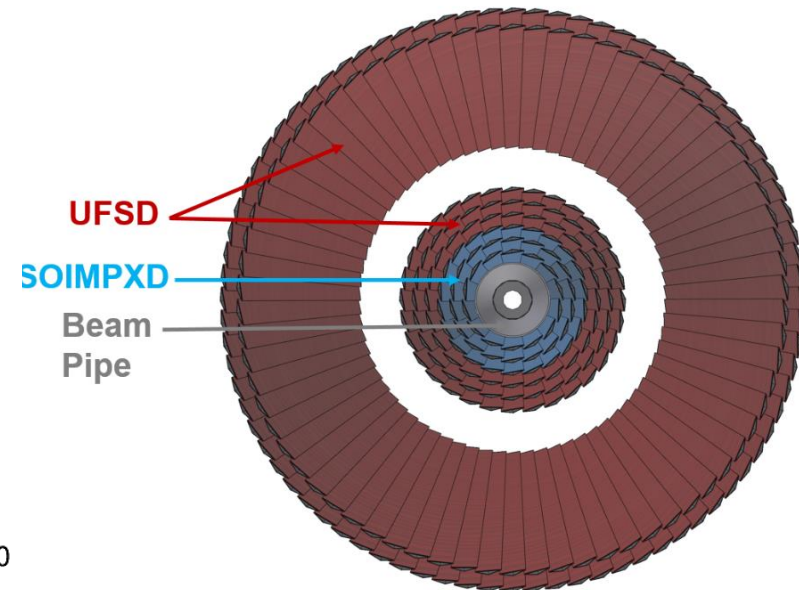
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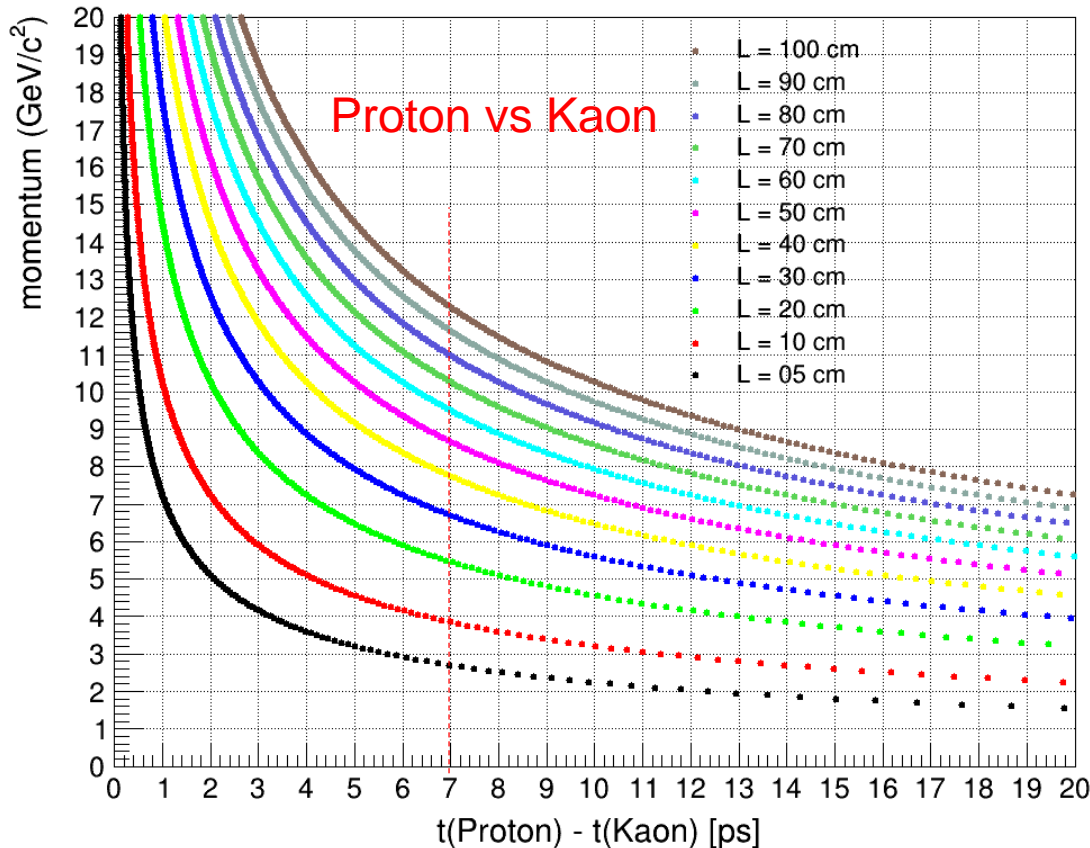




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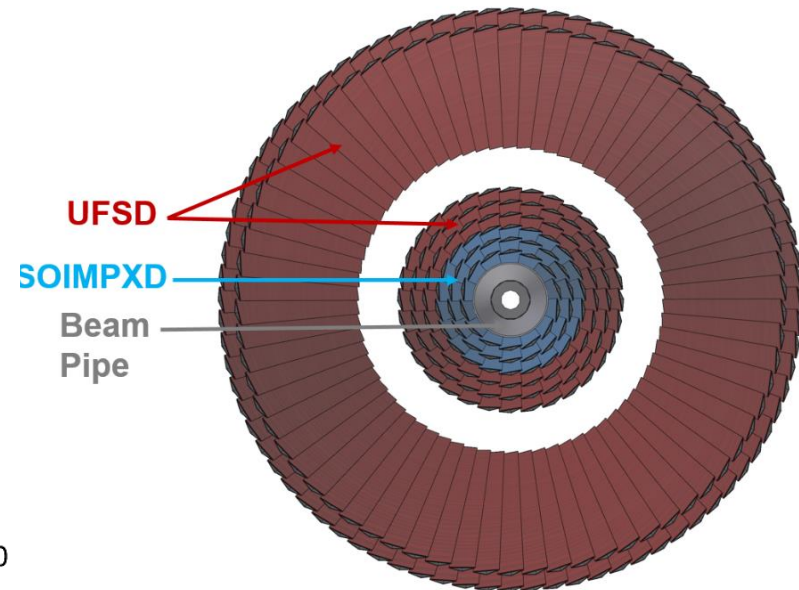
Simulation is needed to confirm PID with UFSD

Time of Flight: this can be used for PID



$$T_1 - T_2 = \frac{L}{c} \left( \sqrt{1 + \frac{m_1^2}{p^2}} - \sqrt{1 + \frac{m_2^2}{p^2}} \right)$$

$L$ : path length (Silicon Barrel Position)



# Summary

Silicon-On-Insulator Monolithic PiXel

Detector (**SOIMPXD**) and Ultra-Fast Silicon

Detector (**UFSD**) provide best of silicon detector technology for tracking and particle identification:

- **SOIMPXD**: best position resolution  $< 1 \mu\text{m}$
- **UFSD**: best timing resolution  $< 16 \text{ ps}$  (5 to 10 ps)

**SOIMPXD + UFSD = Silicon Hybrid Detector** is state-of-art of silicon detector technology which EIC can use to search for new physics discoveries.

Silicon Hybrid Detector = SOIMPXD + UFSD

Coverage:  $\phi = 2\pi$   
 $|\eta| < 5.0$

